What Is Claimed Is:

1. A measurement system comprising:

at least one stationary array of sensors at a first location to produce a first array of measurement outputs;

at least one scanning sensor at a second location to produce a second array of measurement outputs; and

means for synthesizing an array of measurement outputs by fusing the first and second arrays of measurement outputs.

- 2. The measurement system of claim 1, wherein the stationary and scanning measurements are compared and reconciled so that the measurements made by a plurality of sensors are attributed to the same point on material that is being measured.
- 3. The measurement system of claim 1, wherein the measurements comprise time stamp information, cross direction coordinates, machine direction coordinates, and at least one of machine direction odometer or velocity information.
- 4. The measurement system of claim 1, wherein the synthetic measurement is provided by computing an offset using a recursive least mean square algorithm.
- 5. The measurement system of claim 4, wherein the recursive least mean square algorithm is a Kalman filter.
- 6. The measurement system of claim 5, wherein the Kalman filter output data is used to compensate for different sensor inputs and bias errors.

- 7. The measurement system of claim 5, wherein the Kalman filter output data is used to compensate for the temporal variations in the biases of an array of stationary sensors.
- 8. The measurement system of claim 1, wherein data measurements from stationary and scanning sensors are compared by a Kalman filter and an offset compensation for the sensor measurement drift is calculated.
- 9. A method for fusing data measurements obtained from plural locations in a product manufacturing process comprising:

measuring a variable of at least one of the product properties and the process with at least one stationary sensor at a first location in the manufacturing process to produce a first output;

measuring the variable of at least one of the product properties and the process with a scanning sensor at a second location in the manufacturing process to produce a second output; and

producing a synthetic measurement by fusing the first and second outputs.

- 10. The method of claim 9, wherein the stationary and scanning measurements are compared and reconciled so that the measurements made by a plurality of sensors are attributed to the same spot on material that is being measured.
- 11. The method of claim 10, wherein the measurements comprise time stamp information, cross direction coordinates, machine direction coordinates, and at least one of machine direction odometer or velocity information.

- 12. The method of claim 9, wherein the synthetic measurement is provided using an offset computed by a recursive algorithm.
- 13. The method of claim 12, wherein the recursive algorithm is a Kalman filter.
- 14. The method of claim 13, wherein the Kalman filter uses different sensor inputs and computes bias errors.
- 15. The method of claim 13, wherein the Kalman filter computes the temporal variations in the biases of an array of stationary sensors.
- 16. The method of claim 9, wherein data measurements from stationary and scanning sensors are compared by a Kalman filter and an offset compensation for the sensor measurement drift is calculated.